## SD CONNECTOR, SMT TYPE.

#### 1. SCOPE

This specification covers performance, tests and quality requirements for the SD CONNECTOR, SMT TYPE.

#### 2. APPLICABLE DOCUMENT

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

Test report: 501-57089

#### 3. REQUIREMENTS

### 3.1. DESIGN AND CONSTRUCTION

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

#### 3.2. MATERIALS

- A. Housing: High Temperature Thermoplastic, UL94V-0, Black Color.
- B. Contact: Phosphor Bronze, Gold plating on contact area, Tin-lead or Tin plated on soldertails, Nickel underplated all over.
- C. Shield: Gold plating on contact area, Nickel underplated all over.

#### 3.3. RATINGS

- A. Current Rating: 0.5 A Max
- B. Voltage Rating: 5 VAC (rms) Max.
- C. Operating temperature: -25°C to +90°C

#### 3.4. TEST CONDITION

The product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1.

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			FZ00-0145-04





# 3.5. TEST REQUIREMENTS AND PROCEDURES SUMMARY

TEST DESCRIPTION	REQUIREMENT	PROCEDURED					
Examination of product	Meets requirements of product Drawing and Tyco Specification	Visual inspection No physical damage					
ELECTRICAL							
Contact Resistance	100mΩ Max.	Maximum test current and 20mV					
		maximum open circuit voltage.					
	Card detect contact: $150m\Omega$ Max	IEC 512 part 2, test 2a, except 100mA					
Insulation Resistance	1000MΩ Min (initial)	500V DC between adjacent contacts of					
	100M $\Omega$ Min (finial)	mated connectors. IEC 512 part 2, test 3a, method C					
Dielectric Withstanding	No creeping discharge or flashes	500V AC rms.1 minute, test between					
Voltage Resistance	occur.	adjacent contacts of unmated samples.					
		EIA-364-20					
	MECHANICAL						
Pulling and Insertion Force	Pulling Force: 2N Min.	Test rate of 25 mm/minute.					
	Insertion Force: 40N Max.	IEC 512 part 7					
Vibration	No physical damage	With cards applying DC 100mA,cards					
		mated connectors to 10 to 2000Hz of vibration for 4 hour in each of 3 mutually					
		perpendicular planes					
		IEC 512 part 4, test 6d.					
Physical Shock	No physical damage	With cards applying DC 100mA,cards					
1,0.00.	The projection damage	mated connectors to 5G's peak					
		acceleration, half sine wave pulses of 11					
		milliseconds, 3 shocks applied along 3					
		mutually perpendicular planes, total 9					
		shocks					
		IEC 512 part 4, test 6c. Acceleration is 5G					
Contact Force	2N~20N	IEC 512 Part 8					
Connector Intensity	No physical damage	Applied Force 10N to main body of connector at no card for Up/ Down/					
		Forward/ Backward directions					
Wrestling (Flapping) Strength	No physical damage	Applied Force 10N to SD card for UP/					
Treating (Flapping) Strength	itto priyoroar darriago	Down/ Right/ Left directions (The card					
		shall be inserted 15mm into the connector					
		from the head of the card)					
Durability	No physical damage	Operation Cycles: 10000 cycles time					
		(push-in push-out), mate and unmated					
		connectors for 500 cycles per hour					
		EIA 364-09					
ENVIRONMENTAL							
Humidity	Contact resistance:120 mΩ Max.	Temperature: 40°C±2°C					
	Insulation resistance: 100 M Ω Max						
	No physical damage	Period: 96 hours.					
		MIL-STD-202F, method 103B,Test condition B					
Salt Spray	No harmful corrosion	Temperature:35°C±2°C					
Can Opiay	No Hamilai comosion	Concentration: 5%					
		Period: 48 hours.					
		MIL-STD-202F, method 101D.					
		5 1 5 1 5 1 1 1 1 1 1 1 1 1 1 1 1					

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Thermal Shock	No physical damage	MIL-STD-202, Method 107G					
		Subject mated Connectors to 100 cycles					
		between -20°C and 65°C. MIL-STD-202F, METHOD 107G, Test					
		condition A, -55 to +85℃, 5 cycles.					
Moisture Resistance	No physical damage	Subject mated connectors to 10 cycles					
		Between -10°C and 65°C at 80~98%					
		relative Humidity.					
		MIL-STD-202, Method106, test condition B					
Temperature Life	No physical damage	Subject mated connectors to 85℃ for 250					
		hours.					
		MIL-STD-202, Method108					
PHYSICAL							
Solderability	The test area shall be covered	Solder temperature: 245°C±5°C					
·	more than 95% of immersed area						
	with flash solder.	MIL-STD-202F, method 208.					
Resistance to Reflow Soldering	No physical abnormalities such as	Solder temperature: Pre-Heat 150~200℃					
Heat	crack and deformation of housing	for 60 sec max. Heat Peak: 265℃ for 5 sec					
	shall be present after the test.	max.					
		MIL-STD-202F method 210A.					

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### 3.6. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE

	Test Group									
Test or Examination		В	С	D	Ш	F	G	Н		J
		Test Sequence (a)								
Examination of Product	1,9	1,8	1,5	1,7	1,6	1,5	1,5	1,9	1,9	1,9
Contact Resistance		2,7	2,4	2,5	2	2,4	2,4	2,6	2,6	2,6
Insulation Resistance	3,7			3,6				3,7	3,7	3,7
DWV	4,8							4,8	4,8	4,8
Pulling and Insertion Force		3,6								
Vibration			3							
Physical Shock Shock				4						
Contact Force					თ					
Connector Intensity		4								
Wrestling Strength					4					
Durability Cycling		5								
Humidity	5									
Salt Spray						ფ				
Solderability					5					
Thermal Shock							3			
Moisture Resistance								5		
Temperature Life									5	
Resistance to Reflow Soldering Heat										5

NOTE: (a) Numbers indicate sequence in which tests are performed.

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